

**Search Notes**

Application/Control No.

09/726,564

Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

NONAKA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
713	193	1/18/2007	ECT
726	26	1/18/2007	ECT
713	189	1/18/2007	ECT
380	201	1/18/2007	ECT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	1/18/2007	ECT
All claims were examined for possible 101 rejection	1/18/2007	ECT
NPL - IEEE EXPLORE	1/18/2007	ECT